Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/724,193	SUNTER, STEPHEN K.
	Examiner	Art Unit	
	Toan M. Le	2863	

SEARCHED

Class	Subclass	Date	Examiner
702	194	5/5/2005	TL
714	727	5/6/2005	TL
326	21	5/6/2005	TL
324	76.15	5/6/2005	TL
Above	Updated	10/7/2005	TL
Above	Updated	2/9/2006	TL
324	76.77	2/9/2006	TL
Above	Updated	8/19/2006	TL
702	199	8/19/2006	TL
324	761	8/19/2006	TL
714	724,704	8/19/2006	TL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Mixed Signal Test Bus	5/6/2005	TL
Boundary Scan, Mixed Signal, Average	5/6/2005	TL
Mixed Signal, Test, Average, Sequence, Difference, IEEE 1149.1, Bus	5/6/2005	TL
Digital Logic Device	5/6/2005	TL
East- See Search History Printout	10/7/2005	TL
IEEE Xplore	8/19/2006	TL
702/194,199; 714/727,724,704; 326/21; 324/76.15,76.77,761 (Data Sequence, Average Voltage)	8/19/2006	**TL**
East- See Search History Printout	8/19/2006	TL